

Amendments to the Specification:

Please replace paragraph [0079] (page 27, lines 1-9) with the following amended paragraph:

[0079] To examine the cause of the change of the magnetic properties, crystallographic orientation of respective CoCrPt/Cr films was examined by X-ray diffraction θ-2θ method. It has been found that the Cr film formed on the [[grass]] glass and Al₂O₃ film showed Cr (110) orientation and the CoCrPt film (magnetic domain control film 11) thereon showed mixed crystal orientation of Co(00.2)Co(10.0)Co(11.0). On the other hand, an intense Co(00.1) peak was observed for the CoCrPt/Cr thin film formed on each of the layers of the stack of magnetoresistive layers-thin film to reveal a structure in which the C axis of the Co hexagonal closed packed crystal structure is intensely oriented in the direction vertical to the film plane. They correspond to the states of State A1 and State A2, respectively, in Fig. 6.